

FNK N-Channel Enhancement Mode Power MOSFET

Description

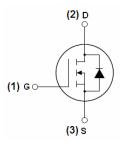
The FNK03N11M uses advanced trench technology and design to provide excellent $R_{\rm DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

- V_{DS} = 30V, I_{D} =13A $R_{DS(ON)}$ < 11mΩ @ V_{GS} =10V $R_{DS(ON)}$ <15mΩ @ V_{GS} =4.5V
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current

Application

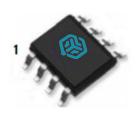
- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply



Schematic diagram



Marking and pin assignment



SOP-8 top view

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
FNK03N11M	FNK03N11M	SOP-8	Ø330mm	12mm	2500 units

Absolute Maximum Ratings (T_A=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	13	Α
Drain Current-Continuous(T _C =100 °C)	I _D (100℃)	9	А
Pulsed Drain Current	I _{DM}	52	Α
Maximum Power Dissipation	P _D	3.0	W
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 150	$^{\circ}$

Thermal Characteristic

Thermal Resistance, Junction-to-Case (Note 2)	$R_{ heta JC}$	40	°C/W





Electrical Characteristics (T_A=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics			•				
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	30	33	-	V	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =30V,V _{GS} =0V -		-	1	μA	
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA	
On Characteristics (Note 3)			•				
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	1.0	1.5	2.5	V	
Dunin Course On Otata Desistance		V _{GS} =10V, I _D =10A		6.5	11	mΩ	
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =7A	8.4 15		15	— mg	
Forward Transconductance	g FS	V _{DS} =5V,I _D =10A	15	-	-	S	
Dynamic Characteristics (Note4)			•				
Input Capacitance	C _{lss}	\/ 45\/\/ 0\/	-	1200	-	PF	
Output Capacitance	C _{oss}	V _{DS} =15V,V _{GS} =0V,	-	200	-	PF	
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	130	-	PF	
Switching Characteristics (Note 4)			•				
Turn-on Delay Time	t _{d(on)}		-	3.5	-	nS	
Turn-on Rise Time	t _r	V_{DD} =25 V , I_D =1 A	-	3.2	-	nS	
Turn-Off Delay Time	t _{d(off)}	V_{GS} =15 V , R_{GEN} =6 Ω	-	34	-	nS	
Turn-Off Fall Time	t _f		-	10	-	nS	
Total Gate Charge	Qg	\/ -15\/ -12A	-	25	-	nC	
Gate-Source Charge	Q _{gs}	V_{DS} =15V, I_{D} =13A, V_{GS} =10V	-	15.5	-	nC	
Gate-Drain Charge	Q _{gd}	V _{GS} -10V	-	13.5	-	nC	
Drain-Source Diode Characteristics							
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =10A	-	-	1.2	V	
Diode Forward Current (Note 2)	Is		-	-	13	Α	
Reverse Recovery Time	t _{rr}	IF = 14A VDS=15V		120		nS	
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	80		nC	

Notes:

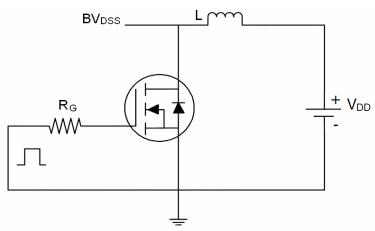
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production

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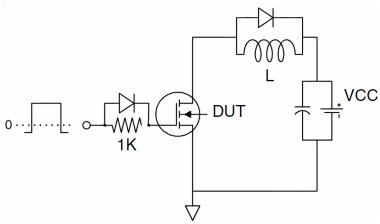


Test Circuit

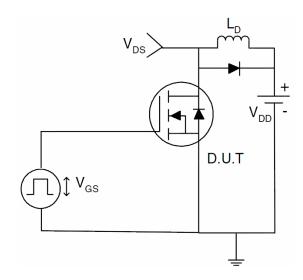
1) E_{AS} Test Circuits



2) Gate Charge Test Circuit:



3) Switch Time Test Circuit:



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Typical Electrical and Thermal Characteristics (Curves)

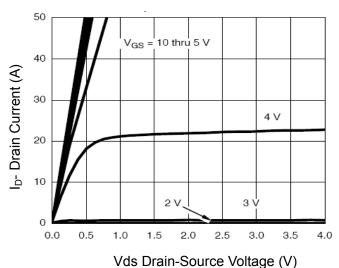


Figure 1 Output Characteristics

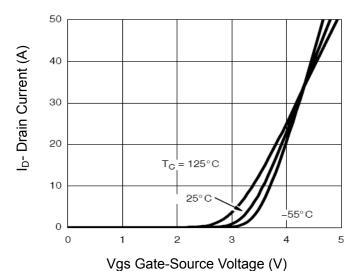
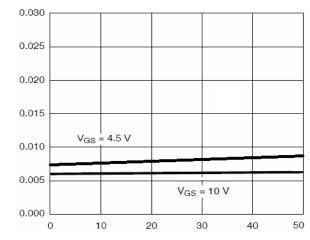


Figure 2 Transfer Characteristics



Rdson On-Resistance(Ω)

I_D- Drain Current (A) Figure 3 Rdson- Drain Current

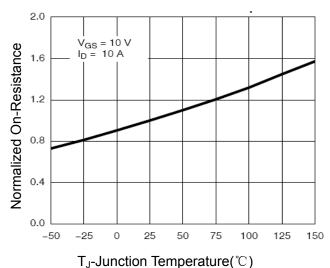


Figure 4 Rdson-JunctionTemperature

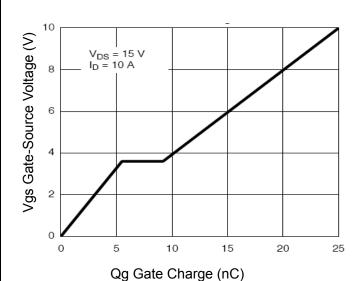


Figure 5 Gate Charge

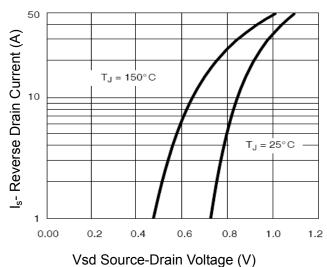
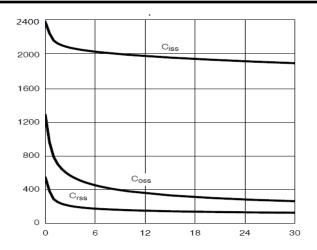


Figure 6 Source- Drain Diode Forward

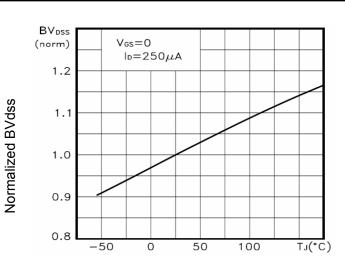


C Capacitance (pF)



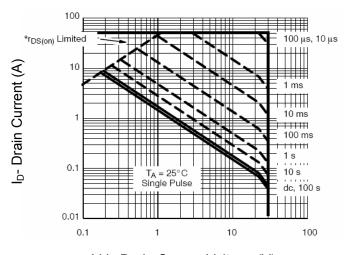
Vds Drain-Source Voltage (V)

Figure 7 Capacitance vs Vds



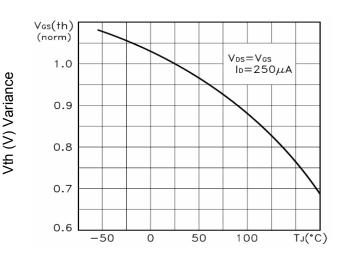
 T_J -Junction Temperature($^{\circ}$ C)

Figure 9 BV_{DSS} vs Junction Temperature



Vds Drain-Source Voltage (V)

Figure 8 Safe Operation Area



 T_J -Junction Temperature($^{\circ}$ C)

Figure 10 V_{GS(th)} vs Junction Temperature

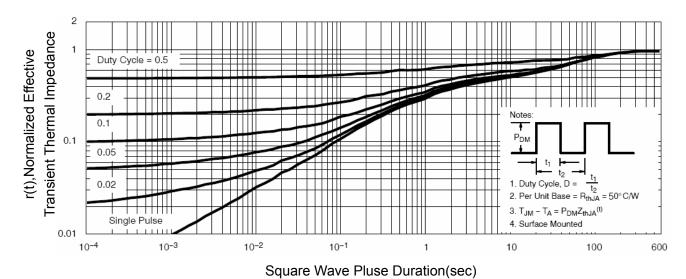
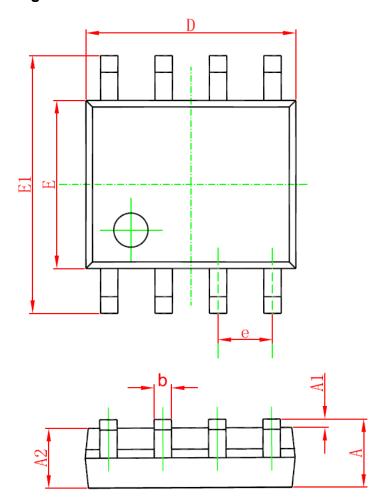
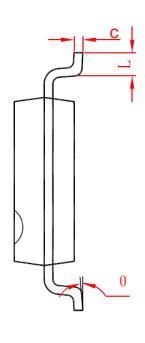


Figure 11 Normalized Maximum Transient Thermal Impedance



SOP-8 Package Information





Symbol	Dimensions I	n Millimeters	Dimensions In Inches		
	Min	Max	Min	Max	
A	1. 350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0. 004	0. 010	
A2	1. 350	1. 550	0. 053	0. 061	
b	0. 330	0. 510	0. 013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
Е	3. 800	4. 000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1. 270	0. 016	0. 050	
θ	0°	8°	0°	8°	

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